

Chinese Name	Task Name	Duration	Start	Finish	Gantt Chart																																													
					H2	H1	H2	2018	H1	H2	2019	H1	H2	2020	H1	H2	2021	H1	H2	2022	H1	H2	2023	H1	H2	2024	H1	H2	2025	H1	H2	2026	H1	H2	2027	H1	H2	2028	H1	H2	2029	H1	H2	2030	H1	H2	2031	H1	H2	2032
2	硅基探测器关键技术验证	Key technology verification of silicon track detector	1261 days	18/5/1	23/2/28	Key technology verification of silicon track detector																																												
2.1	力学支撑结构	Mechanical support structure	934 days	18/5/1	21/11/26	Mechanical support structure																																												
2.1.1	探测器模块几何排布优化	Layout Optimization	436 days	18/5/1	19/12/31	Layout Optimization																																												
2.1.2	探测器模块的结构初步设计	Preliminary design of ladder supporting structure	130 days	18/5/1	18/10/29	Preliminary design of ladder supporting structure																																												
2.1.3	探测器整机结构初步设计	Preliminary design of detector supporting structure	260 days	18/10/30	19/10/28	Preliminary design of detector supporting structure																																												
2.1.4	支撑结构的工程图设计	Engineering plot design of supporting structure	523 days	19/5/1	21/4/30	Engineering plot design of supporting structures																																												
2.1.5	制造模块的力学支撑结构样品	production of prototype of ladder support	87 days	20/12/31	21/4/30	production of prototype of ladder support																																												
2.1.6	探测器模块的结构最终设计	Final design of ladder supporting structure	43 days	21/5/3	21/6/30	Final design of ladder supporting structure																																												
2.1.7	探测器整机的结构最终设计	Final design of detector supporting structure	416 days	19/10/29	21/6/1	Final design of detector supporting structure																																												
2.1.8	制造探测器整机支撑结构	Manufacture supporting structure of detector	128 days	21/6/2	21/11/26	Manufacture supporting structure of detector																																												
2.1.9	完成所有力学支撑结构的研制	Complete the Manufacture of all mechanical support structures	0 days	21/11/26	21/11/26	11/26 Complete the Manufacture of all mechanical support structures																																												
2.2	传感器	The sensor	919 days	18/5/1	21/11/5	The sensor																																												
2.2.1	传感器像素内的电子学设计，抗辐照元件设计	Electronics design in sensor pixel, design of anti - irradiation element	170 days	18/5/1	18/12/24	Electronics design in sensor pixel, design of anti - irradiation element																																												
2.2.2	外围数字电路、触发、时钟与电源等模块设计，与芯片抗辐照性能模拟	Peripheral digital circuit, trigger, clock and power supply ladder design, and chip anti-radiation performance simulation	261 days	18/5/1	19/4/30	Peripheral digital circuit, trigger, clock and power supply ladder design, and chip anti-radiation performance simulation																																												
2.2.3	第一次多项目晶圆（MPW）流片	1st MPW	100 days	19/6/17	19/11/1	1st MPW																																												
2.2.4	第二次多项目晶圆（MPW）流片	2nd MPW	90 days	20/2/18	20/6/22	2nd MPW																																												
2.2.5	整合全功能的小面积芯片设计	Integration of fully functional small area chip design	190 days	19/5/1	20/1/21	Integration of fully functional small area chip design																																												
2.2.6	第三次多项目晶圆（MPW）流片	3rd MPW	108 days	21/1/1	21/6/1	3rd MPW																																												
2.2.7	设计大面积，全功能的传感器芯片	Design large area, full function sensor chip	328 days	20/5/13	21/8/13	Design large area, full function sensor chip																																												
2.2.8	第一次工程批硅晶圆加工	First engineering batch silicon wafer processing	60 days	21/8/16	21/11/5	First engineering batch silicon wafer processing																																												
2.3	读出电子学与数据获取系统	Readout electronix and data acquisition system	1066 days	18/5/1	22/5/31	Readout electronix and data acquisition system																																												
2.3.1	为初次MPW的芯片研制前端电路板	Development of the front end circuit board for the initial MPW chip	261 days	18/5/1	19/4/30	Development of the front end circuit board for the initial MPW chip																																												
2.3.2	研制单个传感器芯片的数据获取系统	Development of data acquisition system for a single sensor chip	220 days	19/5/1	20/3/3	Development of data acquisition system for a single sensor chip																																												
2.3.3	ladder的读出电子学	ladder readout electronic	218 days	20/8/31	21/6/30	ladder readout electronic																																												
2.3.4	研制单个探测器模块的数据获取系统	Development of data acquisition system for a single detector ladder	472 days	20/3/12	21/12/31	Development of data acquisition system for a single detector ladder																																												
2.3.5	原型机的读出电子学	Prototype readout electronic	132 days	21/7/1	21/12/31	Prototype readout electronic																																												
2.3.6	研制探测器原型机的数据获取系统	Development of data acquisition system for the prototype detector	107 days	22/1/3	22/5/31	Development of data acquisition system for the prototype detector																																												
2.4	探测器原型机整体设计与组装	The overall design and assembly of the prototype	1066 days	18/5/1	22/5/31	The overall design and assembly of the prototype																																												
2.4.1	制定探测器模块的组装流程	Develop the assembly process of detector ladder	260 days	18/5/1	19/4/29	Develop the assembly process of detector ladder																																												
2.4.2	制定探测器原型机的组装流程，开发自动组装系统	Develop the assembly process of detector prototype and develop the automatic assembly system	430 days	19/4/30	20/12/21	Develop the assembly process of detector prototype and develop the automatic assembly system																																												
2.4.3	探测模块模型试制	detector ladder trail production	66 days	21/4/30	21/7/30	detector ladder trail production																																												
2.4.4	组装与调试首批探测器模块	Assemble and test the first detector ladder	38 days	21/11/24	22/1/14	Assemble and test the first detector ladder																																												
2.4.5	组装与调试探测器模块	Assemble and test the rest of detector ladder	75 days	22/1/17	22/4/29	Assemble and test the rest of detector ladders																																												
2.4.6	组装与调试探测器原型机	Assemble and debug detector prototype	22 days	22/5/2	22/5/31	Assemble and debug detector prototype																																												
2.4.7	完成探测器原型机的组装调试	Complete the assembly and debugging of detector prototype	0 days	22/5/31	22/5/31	5/31 Complete the assembly and debugging of detector prototype																																												
2.5	测试与数据分析	Test and data analysis	1086 days	19/1/1	23/2/28	Test and data analysis																																												
2.5.1	对第一次MPW芯片做测试	Test 1st MPW chip	157 days	19/11/4	20/6/9	Test 1st MPW chip																																												
2.5.2	对第二次MPW的芯片做测试	Test the second MPW chip	93 days	20/8/4	20/12/10	Test the second MPW chip																																												
2.5.3	对第三次MPW的芯片做测试	Test the third MPW chip	53 days	21/6/2	21/8/13	Test the third MPW chip																																												
2.5.4	对工程批芯片做测试	Test engineering chip	12 days	21/11/8	21/11/23	Test engineering chip																																												
2.5.5	束流测试与数据分析	Beam testing and data analysis	1086 days	19/1/1	23/2/28	Beam testing and data analysis																																												
2.5.5.1	束流测试模拟、重建和分析软件开发	development of the simulaiton, reconstruction and analysis software	784 days	19/1/1	21/12/31	development of the simulaiton, reconstruction and analysis software																																												
2.5.5.1.1	模拟软件开发	development of the simulaiton software	261 days	19/1/1	19/12/31	development of the simulaiton software																																												
2.5.5.1.2	重建软件开发	development of the reconstruction software	784 days	19/1/1	21/12/31	development of the reconstruction software																																												
2.5.5.2	分析软件开发	development of the analysis software	784 days	19/1/1	21/12/31	development of the analysis software																																												
2.5.5.3	束流测试实验	Beam test experiment	60 days	22/6/1	22/8/23	Beam test experiment																																												
2.5.5.4	数据分析	The data analysis	85 days	22/8/24	22/12/20	The data analysis																																												
2.5.5.5	发表测试结果，撰写终期报告	Publish test results and write final report	50 days	22/12/21	23/2/28	Publish test results and write final report																																												
2.5.6	完成项目终期报告	Complete the final project report	0 days	23/2/28	23/2/28	2/28 Complete the final project report																																												